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501.38036X00

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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JAN 24 2000

GROUP 2700

Applicant(s): H. SHISHIDO, et al

Serial No.: 09/473,296

Filed: December 28, 1999

For: METHOD AND EQUIPMENT FOR DETECTING PATTERN
DEFECT

Group: 2785

Examiner:

PRELIMINARY AMENDMENT

Commissioner for Patents
Washington, D.C. 20231

July 20, 2000

Sir:

The following preliminary amendments and remarks are respectfully submitted in connection with the above-identified application.

IN THE SPECIFICATION:

Please replace the original specification with the attached Substitute Specification.

BEST AVAILABLE COPY

IN THE CLAIMS:

Please amend the claims as follows:

- Claim 1, line 2, before "laser" (first occurrence) insert --a--;
- same line 2, delete "means";
- line 4, delete "means";
- line 14, delete "detecting an";
- line 15, delete "image of said sample".